Search Notes					

Application/Control No.	Applicant(s)/Patent under Reexamination
10/676,961	PON ET AL.
Examiner	Art Unit
Chris C. Chu	2815

SEARCHED					
Class	Subclass	Date	Examiner		
257	723, 686, 685, 646, 693 & 777	12/27/2004	C.C.		
257	784 & 786	12/27/2004	C.C.		
257	676	12/27/2004	C.C.		
361	760	12/27/2004	C.C.		
438	108 & 109	12/27/2004	C.C.		
438	612	12/27/2004	C.C.		
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
·	DATE	EXMR		
Searched in US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; and IBM_TDB;	12/27/2004	C.C.		
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